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**Junhua Pan
James C. Wyant
Hexin Wang**
Editors

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Contents

xxiii	Conference Committee
xxv	Symposium Committees
xxvii	Introduction
xxix	Attendees of AOMATT 2007 photo

Part One

SESSION 3-1

- 6723 02 **Method for 3D profilometry measurement based on contouring moiré fringe** [6723-01]
Z. Shi, J. Lin, Guangdong Univ. of Technology (China)
- 6723 03 **19-element sensorless adaptive optical system based on modified hill-climbing and genetic algorithms** [6723-02]
P. Yang, W. Yang, Y. Liu, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China); S. Hu, Institute of Optics and Electronics (China); M. Ao, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China); B. Xu, W. Jiang, Institute of Optics and Electronics (China)
- 6723 04 **Edge detection in optical images using auto-organization** [6723-03]
F. Liu, L. Dong, Y. He, W. Fan, Hebei Univ. (China)
- 6723 05 **Quantitative analysis of multi-component gas mixture based on AOTF-NIR spectroscopy** [6723-04]
H. Hao, Xi'an Jiaotong Univ. (China) and Taiyuan Iron and Steel Co. (China); Y. Zhang, J. Liu, Xi'an Jiaotong Univ. (China)
- 6723 06 **Research on acupuncture points and cortical functional activation position in cats by infrared imaging detection** [6723-05]
S. Chen, Z. Sha, S. Wang, H. Wen, Hebei Univ. of Science & Technology (China)
- 6723 07 **Edge detection of grain image and algorithm of extra work** [6723-06]
Y. Wang, B. Qin, S. Si, Shandong Univ. (China)

SESSION 3-2

- 6723 08 **Research on real-time measurement and grading method for pearl color** [6723-07]
F. Zhu, K. Wu, L. Ma, J. Zhou, Hangzhou Dianzi Univ. (China)
- 6723 09 **Method of computer-aided precise alignment of unstable resonator** [6723-08]
W. Zhang, W. Liu, Z. Liu, National Univ. of Defense Technology (China)

- 6723 0A **Mid-frequency surface error test with a Foucault apparatus** [6723-09]
B. Xuan, J. Li, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of Chinese Academy of Sciences (China); S. Song, J. Xie, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6723 0B **Null compensation test with zero-power corrector** [6723-10]
P. Hao, K. Li, L. Yuan, Tongji Univ. (China)

SESSION 3-3

- 6723 0C **Ratio measurement of reactive ion beam etching rate using optical interferometry** [6723-11]
D. Zhang, Y. Huang, Z. Ni, S. Zhuang, Univ. of Shanghai for Science and Technology (China)
- 6723 0D **Study on residual stresses of Ni-based WC coating by laser remelting based on XRD** [6723-12]
Z. Chen, Jiangsu Polytechnic Univ. (China) and Jiangsu Univ. (China); D. Kong, Jiangsu Polytechnic Univ. (China); L. Wang, Jiangsu Univ. (China); X. Zhu, X. Zhao, Jiangsu Polytechnic Univ. (China)
- 6723 0E **3D displacement measurement with a single camera based on digital image correlation technique** [6723-13]
W. Sun, E. Dong, X. He, Southeast Univ. (China)
- 6723 0F **High accuracy measurements of objects with multiple reflective surfaces with wavelength shifting interferometry** [6723-14]
S. Tang, R. E. Bills, K. Freischlad, KLA-Tencor (USA)
- 6723 0G **Measurement of diameters of ultrafine particles based on characteristics of fluctuation of scattered light** [6723-15]
J. Shen, S. Yang, Q. Ding, Y. Cheng, Shandong Univ. of Technology (China)

SESSION 3-4

- 6723 0H **Measurement of lenses' power based on moiré deflection technology** [6723-16]
Q. Wang, Soochow Univ. (China); J. Yu, Soochow Univ. (China), Wenzhou Medical College (China), and Ministry of Health (China); H. Chen, Wenzhou Medical College (China) and Ministry of Health (China)
- 6723 0I **Passive ring resonator gyroscope using high-order dispersion** [6723-17]
X. Luo, Z. Li, Peking Univ. (China)
- 6723 0J **Heterodyne interferometry for real-time displacement measurement by phase-to-amplitude conversion technique** [6723-18]
H.-K. Teng, K.-C. Lang, Nan-Kai Institute of Technology (Taiwan)
- 6723 0K **High resolution detection system of capillary electrophoresis** [6723-19]
J. Wang, L. Q. Wang, Y. Shi, Zhejiang Univ. (China); H. Zheng, Zhejiang Univ. (China) and Fujian Normal Univ. (China); Z. K. Lu, Zhejiang Univ. (China)

SESSION 3-5

- 6723 0L **Imaging aberrations from null correctors** [6723-20]
C. Zhao, J. H. Burge, College of Optical Sciences/The Univ. of Arizona (USA)
- 6723 0M **Analysis of infrared interferometry with laser noises** [6723-21]
X. Cao, R. Zhang, Sichuan Univ. (China)
- 6723 0N **High-resolution lensless Fourier transform holography for microstructure imaging** [6723-22]
J. Zhao, D. Wang, Beijing Univ. of Technology (China); H. Wang, Beijing Univ. of Technology (China) and Hebei Univ. of Engineering (China); J. Xie, Beijing Univ. of Technology (China)
- 6723 0O **Method for self-mixing interference signal analysis based on Kalman filter** [6723-23]
Y. Zhang, Y. Wang, X. Luo, Yanshan Univ. (China); R. Ren, Academy of Armored Force Engineering (China)
- 6723 0P **Wavefront fitting and evaluation of fiber point diffraction interferometer** [6723-24]
S. Wu, D. Sha, J. Lin, T. Zhou, L. Chen, L. Nie, Beijing Institute of Technology (China)

SESSION 3-6

- 6723 0Q **Whole visible range imaging ellipsometry** [6723-25]
H.-W. Wang, Mingchi Univ. of Technology (Taiwan); Y.-C. Hsieh, K.-P. Chuang, F.-S. Yang, C. I Wu, Industrial Technology Research Institute (Taiwan)
- 6723 0R **Study on SD-LMS adaptive signal processing algorithm in space optical communication** [6723-26]
J. Chen, H. Jiang, Z. Liu, Huazhong Univ. of Science and Technology (China)
- 6723 0S **Rapid detection of soluble content in beer using spectroscopic technique based on LS-SVM algorithm model** [6723-27]
L. Wang, Y. He, F. Liu, Zhejiang Univ. (China)

SESSION 3-7

- 6723 0T **Light scattering characterization of self-affine fractal surfaces by a new algorithm of Levenberg-Marquardt method** [6723-28]
N. Zhang, Shandong Normal Univ. (China) and Shandong Jianzhu Univ. (China); C. Liu, G. Liu, M. Liu, C. Cheng, Shandong Normal Univ. (China)
- 6723 0U **Method for measuring optical fiber core no-circularity** [6723-29]
S. Xiao, X. Zhang, X. Mao, Nanjing Univ. of Information Science and Technology (China)
- 6723 0V **Measurement of out-of-plane displacement with a digital real-time holography** [6723-30]
R. X. Guo, Z. B. Fan, H. Y. Qin, X. Xu, J. C. Li, Kunming Univ. of Science and Technology (China)
- 6723 0W **Measurement of pH of rice wines using Vis/NIR spectroscopy and least squares-support vector machine** [6723-31]
Y. He, F. Liu, L. Wang, Zhejiang Univ. (China)

- 6723 0X **Transition of luminance mode in dielectric barrier discharge** [6723-32]
Y. Li, L. Dong, W. Fan, Hebei Univ. (China)

SESSION 3-8

- 6723 0Y **Method for eliminating the influence of light intensity modulation in sinusoidal phase modulating laser diode interferometer** [6723-33]
Z. Li, X. Wang, B. Huang, P. Bu, D. Zheng, Shanghai Institute of Optics and Fine Mechanics (China) and Graduate Univ. of Chinese Academy of Sciences (China)
- 6723 0Z **New parallel plate interferometer for measuring angular displacement** [6723-34]
D. Zheng, Shanghai Institute of Optics and Fine Mechanics (China) and Graduate School of Chinese Academy of Sciences (China); X. Wang, Shanghai Institute of Optics and Fine Mechanics (China); O. Sasaki, Niigata Univ. (Japan)

SESSION 3-9

- 6723 10 **Phase transition characteristics of tungsten and tantalum doped VO₂ polycrystalline thin films formed by ion beam enhanced deposition** [6723-35]
J. Li, D. Dan, N. Yuan, T. Xie, Jiangsu Polytechnic Univ. (China)
- 6723 11 **Determination of subsurface damage in Nd-doped phosphate glasses** [6723-36]
W. Zhang, J. Zhu, Shanghai Institute of Optics and Fine Mechanics (China)
- 6723 12 **Application of adaptive optics in complicated and integrated spatial multisensor system and its measurement analysis** [6723-37]
Q. Ding, C. Guo, M. Cai, H. Liu, Luoyang Institute of Electro-Optical Equipment (China)
- 6723 13 **Study on resolution of subdivision technique for grating based on CMOS microscopic imaging** [6723-38]
B. Yuan, X. Q. Cao, H. M. Yan, Zhejiang Univ. (China)

POSTER SESSION

- 6723 14 **Numerical simulation of rough surface bidirectional reflectance distribution function (BRDF)** [6723-39]
W. Feng, Q. Wei, S. Wang, Y. Wu, S. Liu, D. Wu, Z. Liu, Anhui Institute of Optics and Fine Mechanics (China)
- 6723 15 **Dynamic photoelectric autocollimator based on two-dimension position sensitive detector** [6723-40]
J. Zhang, Beijing Institute of Space Mechanics and Electricity (China); T. Fan, X. Cao, Institute of Optics and Electronics (China)
- 6723 16 **Study on voltage biasing technique for spectral response measurement of multi-junction solar cell** [6723-41]
D. Ran, S. Zhang, J. Zhang, X. Zhang, F. Wan, Hebei Univ. of Technology (China)

- 6723 17 **Research on cruur measurement and its data processing method** [6723-42]
D. Ran, S. Zhang, W. Zhou, Y. Zhang, Hebei Univ. of Technology (China)
- 6723 18 **Instrument for testing the near and far field distribution of semiconductor laser** [6723-43]
X. Jiang, C. Zhuang, Y. Zhao, Chang Chun Science and Technology Univ. (China)
- 6723 19 **Optoelectronic noncontact measurement method for detecting the diameter of a bullet**
[6723-44]
X. Zhou, H. Zhang, Armor Technique Institute of PLA (China); T. Sun, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China); Q. Wang, X. Zhai, Armor Technique Institute of PLA (China)
- 6723 1A **Optical and morphological characteristics of organic thin films for optoelectronic devices**
[6723-45]
Z. Zhong, F. Sun, South-Central Univ. for Nationalities (China)
- 6723 1B **Specular and diffuse reflectance of silicon photodiodes** [6723-46]
Y. Zhou, T. Xu, H. Chen, Shenzhen Academy of Metrology and Quality Inspection (China)
- 6723 1C **Measurement of ultrasound field pressure with laser Doppler vibrometer** [6723-47]
T. Xu, R. Lu, H. Chen, Y. Zhou, Shenzhen Academy of Metrology and Quality Inspection (China)
- 6723 1D **Fringe analysis with Hilbert transform and its application to the measurement of aspheric mirror** [6723-48]
J. Lv, Nanjing Univ. of Finance and Economics (China); M. Wang, H. Huan, Nanjing Normal Univ. (China); B. Zhang, Nanchang Univ. (China)
- 6723 1E **Angle deviation for coupling loss in fiber collimator packaging** [6723-49]
J. Qiu, Shanghai Univ. of Engineering Science (China); F. He, Shanghai Academy of Spaceflight Technology (China)
- 6723 1F **Lock-in thermography for evaluation of destruction area and determination of depth**
[6723-50]
Z. Wang, J. Liu, J. Dai, Harbin Institute of Technology (China)
- 6723 1G **Research on lossless detection technology of aero-engine blade** [6723-51]
W. Liu, Changchun Univ. of Science and Technology (China) and Aviation Univ. of Air Force (China); X. Zhai, C. Zhang, Changchun Univ. of Science and Technology (China)
- 6723 1H **Research and design of intelligent robot control system based on infrared and ultrasonic technology** [6723-52]
X.-L. Wen, Zhengzhou Institute of Aeronautical Industry Management (China)
- 6723 1I **Research on the application of multifunctional firearm test equipment in range testing technology** [6723-53]
C. Zhang, H. Ma, X. Zhai, Changchun Univ. of Science and Technology (China)
- 6723 1J **Research of space encoding and matching method in a stereo vision measurement system** [6723-54]
G. Chen, D. Ye, H. Chen, R. Che, Harbin Institute of Technology (China)

- 6723 1K **Study on laser damage properties of thin films** [6723-55]
J. Su, J. Xu, S. Xie, Xi'an Institute of Technology (China)
- 6723 1L **Design of new-style integrated verification device for optical theodolites** [6723-56]
X. Guo, Z. Zhu, H. Wu, L. Ding, Xi'an Research Institute of High-tech (China)
- 6723 1M **Optical multichannel analyzer constructed with 4400 system for glass surface and thin film measurement** [6723-57]
Z. Gu, Univ. of Shanghai for Science and Technology (China); R. Ye, Shanghai Institute of Optics and Fine Mechanics (China); Z. Wang, Univ. of Shanghai for Science and Technology (China); P. Liang, Shanghai Institute of Optics and Fine Mechanics (China)
- 6723 1N **3D deformation measurement by digital speckle correlation method and stereo vision** [6723-58]
H. Chen, G. Chen, D. Ye, R. Che, Harbin Institute of Technology (China)
- 6723 1O **Correlation function of angle-of-arrival measurements with one-dimensional Shack-Hartmann wavefront sensor** [6723-59]
S. Huang, W. Li, P. Zhou, Y. Geng, National Univ. of Defense Technology (China)
- 6723 1P **Analysis for nonlinear error of improved 2D-PSD and its applications** [6723-60]
T. Li, S. Wang, B. Tan, H. Yan, Shandong Univ. of Technology (China)
- 6723 1Q **Study on living object identification based on genetic algorithms** [6723-61]
Y. Wang, M. Xiong, S. Jia, Dalian Maritime Univ. (China)
- 6723 1R **Study on initiative vibration absorbing technology of optics in strong disturbed environment** [6723-62]
S. Jia, M. Xiong, X. Zou, Dalian Maritime Univ. (China)
- 6723 1S **Research on 3-D device for infrared temperature detection** [6723-63]
S. Chen, S. Jiang, J. Hou, S. Chen, Hebei Univ. of Science and Technology (China)
- 6723 1T **Precision measurement for micro size based on support vector regression** [6723-64]
Q. He, L. Wang, Z. Yu, Jilin Univ. (China); Q. Che, First Automobile Workers Import and Export Corp. (China)
- 6723 1U **Research of fabrication and testing technology of monocrystalline silicon optical elements with super-smooth surfaces** [6723-65]
C. Xue, F. Huo, Changchun Univ. of Science and Technology (China); C. Zhou, Changchun Xinxin Optoelectronic Institute of Spaceflight Technology (China)
- 6723 1V **Method for testing aspheric surface with wavelength scanning interferometry** [6723-66]
C. Xue, F. Huo, Changchun Univ. of Science and Technology (China); H. Lv, Mcoptics Co. Ltd. (China)
- 6723 1W **Research on the measuring method of the slope error of EUV/x-ray optical elements and measuring apparatus of long trace profiler** [6723-67]
C. Xue, F. Huo, Changchun Univ. of Science and Technology (China); C. Zhou, W. Deng, Changchun Xinxin Optoelectronic Institute of Spaceflight Technology (China)

- 6723 1X **Three-dimensional surface measurement system based on projected fringe model** [6723-68]
S. Gai, F. Da, Southeast Univ. (China)
- 6723 1Y **Research on magnetic intensity test based on light speed modulating with inner interfering** [6723-69]
Y. Li, M. Li, G. Zheng, S. Zhuang, Univ. of Shanghai for Science and Technology (China)
- 6723 1Z **Novel algorithm to improve sampling frequency of LSF** [6723-70]
W. Ma, C. Cai, L. Yang, Xi'an Technological Univ. (China)
- 6723 20 **Research on strain-test based on light speed modulating method in FBG** [6723-71]
M. Li, Y. Li, G. Zheng, Univ. of Shanghai for Science and Technology (China)
- 6723 21 **Dynamic measurement of normal spectral emissivity (at 905nm) by a pulse-heating reflectometric technique** [6723-72]
P. Xiao, J. Dai, Z. Wang, Harbin Institute of Technology (China)
- 6723 22 **Temperature test of photorefractive materials using light speed slowdown method** [6723-73]
Y. Li, M. Li, G. Zheng, S. Zhuang, Univ. of Shanghai for Science and Technology (China)
- 6723 23 **Large area of DLC films with end-hall ion source enhanced chemical vapour deposition** [6723-74]
Y. Pan, L. Hang, Xi'an Technological Univ. (China); Z. Wu, Xidian Univ. (China)

Part Two

- 6723 24 **Development of a new type of optical microscope** [6723-75]
J. Luo, Second Artillery Engineering Institute (China); S. Hou, Second Artillery Engineering Institute (China) and Xi'an Jiaotong Univ. (China); L. Wang, H. Sun, Second Artillery Engineering Institute (China)
- 6723 25 **Research and application of video test system based on FPGA** [6723-76]
X. Zhang, Y. Shan, L. Yang, China Jiliang Univ. (China)
- 6723 26 **BP neural network application on surface temperature measurement system based on colorimetry** [6723-77]
Z. Sun, S. Cai, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); Y. Qiao, W. Zhu, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6723 27 **Research on coal-mine gas monitoring system controlled by annealing simulating algorithm** [6723-78]
M. Zhou, Z. Li, Anhui Univ. of Science and Technology (China)
- 6723 28 **Study on load temperature control system of ground laser communication** [6723-79]
X. Zhai, Changchun Univ. of Science and Technology (China) and Armor Technique Institute of PLA (China); H. Zhang, Armor Technique Institute of PLA (China); W. Liu, C. Zhang, Changchun Univ. of Science and Technology (China); X. Zhou, Armor Technique Institute of PLA (China)

- 6723 29 **Applied research on four-quadrant optoelectronic detector for surface topography measurement** [6723-80]
S. Wang, S. Chang, T. Xie, Huazhong Univ. of Science and Technology (China); X. Wang, Hubei Polytechnic Univ. (China)
- 6723 2A **Analysis for maladjustment properties of passive confocal unstable resonator by using Hartmann-Shack wavefront sensor** [6723-81]
X. Zhang, A. Xiang, ChengDu Univ. of Information Technology (China)
- 6723 2B **Research on fiber grating sensing to fiber loop ringdown** [6723-82]
W. Zhang, Nankai Univ. (China) and Tianjin Univ. of Technology (China); B. Liu, J. Luo, X. Dong, Nankai Univ. (China)
- 6723 2C **High resolution test for large optics with sub-pixel phase retrieval method** [6723-83]
X. Hu, S. Li, Y. Wu, National Univ. of Defense Technology (China)
- 6723 2D **Effect of electric field on oriented poly(vinylidene fluoride) (PVDF) thin films prepared by vacuum evaporation** [6723-84]
Y. Hui, Xi'an Technological Univ. (China) and Northwestern Polytechnical Univ. (China); W. Liu, W. Luo, Xi'an Technological Univ. (China); C. Yang, Northwestern Polytechnical Univ. (China); X. Niu, Xi'an Technological Univ. (China)
- 6723 2E **Study on automatic measurement of tiny-size** [6723-85]
S. Wang, P. Mu, S. Dai, W. Liu, Univ. of Shanghai for Science and Technology (China)
- 6723 2F **3-D topography measurement by moiré stripe** [6723-86]
J. Qiu, Shanghai Univ. of Engineering Science (China); L. Tan, Shanghai Jiao Tong Univ. (China); P. Zhong, Dong Hua Univ. (China)
- 6723 2G **Spatial coherence measurement of multiple coherent laser combination** [6723-87]
Y. Liu, Y. Cheng, X.-B. Wang, C.-Y. Lu, Wuhan Ordnance Non-Commissioned Officers Academy (China)
- 6723 2H **Laser shaft alignment measurement model** [6723-88]
C. Mo, Changchun Univ. of Science and Technology (China) and Harbin Univ. of Commerce (China); C. Chen, Shenyang Univ. of Technology (China); X. Hou, Northeast Univ. (China); G. Zhang, Changchun Univ. of Science and Technology (China)
- 6723 2I **Method of nonlinear correction of two-dimensional position sensitive detector** [6723-89]
C. Mo, Changchun Univ. of Science and Technology (China) and Harbin Univ. of Commerce (China); M. Wang, Harbin Univ. of Commerce (China); G. Zhang, Changchun Univ. of Science and Technology (China)
- 6723 2J **Research of data acquirement in NIR spectrometer based on SOPC** [6723-90]
K. Yuan, S. Jin, K. Dao, China Jiliang Univ. (China)
- 6723 2K **Pilot study on photonic crystal fiber Raman amplifier** [6723-91]
S. Ruan, M. Zhang, C. Guo, Shenzhen Univ. (China)

- 6723 2L **Research on measurement technology for auto-stereoscopic display vision character based on CCD** [6723-92]
F. Liang, H. Zhang, Nanchang Univ. (China); W. Wang, Hefei Xieli Instrument Manufacture Co., Ltd. (China)
- 6723 2M **Intelligent lightening system of urban and rural road traffic based on pyroelectric infrared detector** [6723-93]
M.-X. Miao, ZhengZhou Institute of Aeronautical Industry Management (China)
- 6723 2N **Wavefront measurement based on active deflectometry** [6723-94]
Y. Liu, X. Su, Q. Zhang, Sichuan Univ. (China)
- 6723 2O **Dynamic deformation measurement and analysis of active stressed lap using optical method** [6723-95]
Q. Zhang, X. Su, Y. Liu, L. Xiang, Sichuan Univ. (China)
- 6723 2P **Structural and optical properties of Al-doped ZnO films coated by RF magnetron sputtering** [6723-96]
Y.-B. Wu, B. Huang, L.-T. Zhang, J. Li, S.-T. Wu, Xiamen Univ. (China)
- 6723 2Q **Detection method and experimental study for pollutant content based on surface plasmon resonance biosensor** [6723-97]
G. Zhao, X. Wang, X. Zhang, Zhejiang Univ. (China)
- 6723 2R **Comparative study of surface roughness with power spectral density and multifractal spectrum** [6723-98]
S. Gan, Univ. of Science and Technology of China (China) and Hefei Univ. of Technology (China); Q. Zhou, Hefei Univ. of Technology (China); Y. Hong, X. Xu, Y. Liu, H. Zhou, T. Huo, S. Fu, Univ. of Science and Technology of China (China)
- 6723 2S **Line-by-line trace gas absorption model and its application for NDIR gas detection technology** [6723-99]
J. Fang, W. Liu, T. Zhang, W. Feng, Key Lab. of Environmental Optics and Technology (China)
- 6723 2T **Nonlinearity-reduced interferometer** [6723-100]
C. Wu, National Tsing Hua Univ. (Taiwan)
- 6723 2U **Research on the effect of phase mask to extend the depth of field of optical system** [6723-101]
X. Chen, S. Dai, C. Xia, Univ. of Shanghai for Science and Technology (China)
- 6723 2V **Laser scattering properties of rough spherical surfaces** [6723-102]
C. Yang, J. Wu, Univ. of Electronic Science and Technology of China (China)
- 6723 2W **New calibration approach for light stripe sensor** [6723-103]
Q. Wu, Shenzhen Univ. (China); X. Su, Sichuan Univ. (China); B. Hui, J. Li, Shenzhen Univ. (China)

- 6723 2X **Three-dimensional digital imaging based on temporal phase unwrapping with parallel DSP** [6723-104]
X. Wang, P. Xiang, Shenzhen Univ. (China) and Tianjin Univ. (China); J. Tian, Shenzhen Univ. (China)
- 6723 2Y **Calculation and analysis of the measurement of the focal length of a lens in a Fizeau interferometer with combination lenses** [6723-105]
J. Yuan, H. Ren, B. Chen, H. Xu, Y. Yang, X. Tang, Y. Ma, K. Ma, D. Yu, W. Li, W. Zheng, Laser Fusion Research Ctr., CAEP (China)
- 6723 2Z **Research on optimum cut direction of quartz transducer** [6723-106]
X. Zhang, K. Yu, J. Zhou, Beijing Univ. of Technology (China)
- 6723 30 **Vectorial shearing interferometer with a high resolution phase shifter** [6723-107]
G. García-Torales, J. L. Flores, Univ. of Guadalajara/CUCEI (Mexico)
- 6723 31 **Approach using sparse bundle adjustment for system calibration of fringe projection 3D profile sensor** [6723-108]
J. Luo, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China); J. Yuan, Institute of Optics and Electronics (China); J. Chen, A. Xiong, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China)
- 6723 32 **Process, reliability test, and interfacial characterization for low temperature wafer direct bonding** [6723-109]
X. Lin, Huazhong Univ. of Science and Technology (China); T. Shi, Huazhong Univ. of Science and Technology (China) and Wuhan National Lab. for Optoelectronics (China); Z. Tang, Wuhan National Lab. for Optoelectronics (China); G. Liao, L. Nie, Huazhong Univ. of Science and Technology (China)
- 6723 33 **Research of laser Doppler velocimetry based on DSPs** [6723-110]
T. Geng, T. Zhang, L. Song, Z. Zhuang, J. Z. Yuan, B. Kun, P. Feng, Harbin Engineering Univ. (China)
- 6723 34 **Research on centralized interlocking monitoring system of OCS switches based on optical communication** [6723-111]
J. Li, L. Wang, X. Gao, Z. Wang, Q. Zhao, Southwest Jiaotong Univ. (China)
- 6723 35 **Research on the dynamic detection system for detecting the height of contact wire** [6723-112]
L. Wang, J. Li, X. Gao, Z. Wang, Q. Zhao, Southwest Jiaotong Univ. (China)
- 6723 36 **Algorithm for computation of off-axis aspheric surface parameters** [6723-113]
S. Li, Y. Fu, Changchun Univ. of Science and Technology (China)
- 6723 37 **Image fusion algorithm for rock fracture detection using wavelet transform** [6723-114]
J. Xu, Univ. of Electronic Science and Technology of China (China); W. Wang, Univ. of Electronic Science and Technology of China (China) and Henan Polytechnic Univ. (China); L. Chen, Chongqing Three Gorges Univ. (China)

- 6723 38 **Analysis of structure and control of the loop-locked ultraprecise 2D flexible hinge stage for optical measurement** [6723-115]
J. Zhang, X. Yang, L. Zhang, Xiamen Univ. (China)
- 6723 39 **Analysis of the measurement error of fibers' position for LAMOST** [6723-116]
Y. Jin, C. Zhai, Y. Teng, X. Xing, Univ. of Science and Technology of China (China)
- 6723 3A **Research on a real-time scanning tunneling microscope data acquisition system** [6723-117]
C. Xu, China Jiliang Univ. (China); B. Xiao, China Jiliang Univ. (China) and Zhejiang Univ. (China); L. Xu, China Jiliang Univ. (China)
- 6723 3B **Study on band gap of photonic crystals with heterostructure** [6723-118]
Y. Lu, Z. Chen, H. Chen, Y. Zheng, Z. Huang, Fujian Normal Univ. (China)
- 6723 3C **Fabrication of MTF measurement system for a mobile phone lens using multi-square objects** [6723-119]
S. M. Hong, J. H. Jo, Hannam Univ. (South Korea); H. Y. Lee, H. S. Yang, Y. W. Lee, I. W. Lee, Korea Research Institute of Standards and Science (South Korea)
- 6723 3D **Imaging resolution of digital holographic microscopy with premagnification** [6723-120]
H. Wang, Beijing Univ. of Technology (China) and Hebei Univ. of Engineering (China); G. Wang, Beijing Univ. of Technology (China) and Henan Institute of Metrology (China); J. Zhao, D. Wang, Beijing Univ. of Technology (China)
- 6723 3E **Interferometric total thickness variation measurement of glass wafer** [6723-121]
J.-B. Song, H.-Y. Lee, Y.-W. Lee, I.-W. Lee, Korea Research Institute of Standards and Science (South Korea)
- 6723 3F **Laser writing system for test of large aspheric surfaces** [6723-122]
H.-G. Rhee, J.-B. Song, D.-I. Kim, Korea Research Institute of Standards and Science (South Korea); K.-S. Ha, S.-K. Hong, Hannam Univ. (South Korea); Y.-W. Lee, I.-W. Lee, Korea Research Institute of Standards and Science (South Korea); J.-H. Jo, Hannam Univ. (South Korea)
- 6723 3G **Structural damage detection with a stabilized optic fiber Fabry-Perot acoustic emission sensor system** [6723-123]
J. Zhao, Y. Shi, N. Shan, X. Yuan, Northwestern Polytechnical Univ. (China)
- 6723 3H **Terahertz technology and application for explosives detection** [6723-124]
J. Xu, X. Li, X. Li, H. Wang, L. Xu, Xi'an Research Institute of High Technology (China)
- 6723 3I **Study on the movement measurement for an objective lens actuator in optical pickup** [6723-125]
X. Cheng, J. Ma, L. Pan, B. Zhang, Tsinghua Univ. (China)
- 6723 3J **Comparative study of two measurements of micro-deformation field with optical method** [6723-126]
Q. Song, Y. Wu, J. Zhu, J. Li, Kunming Univ. of Science and Technology (China)

- 6723 3K **Capillary electrophoresis microchip detecting system based on embedded optical fiber** [6723-127]
W. Yan, Y. Li, L. Ma, Dalian Univ. of Technology (China)
- 6723 3L **Design of compensator for large relative aperture aspherical surface** [6723-128]
G. Shen, Chengdu Fine Optical Engineering Research Ctr. (China)
- 6723 3M **Interferometric measurements of mid-spatial scale surface irregularities** [6723-129]
J. Xu, Q. Xu, L. Chai, Y. Deng, Chengdu Fine Optical Engineering Research Ctr. (China)
- 6723 3N **Design and research on the optical sensor of dissolved oxygen in water based on fluorescence quenching** [6723-130]
L. Sun, W. Dai, Anhui Agricultural Univ. (China); J. Bao, J. Wang, Anhui Institute of Optics and Fine Mechanics (China)
- 6723 3O **Testing smooth surface characteristics based on thermal infrared polarization** [6723-131]
L. Sun, Anhui Agricultural Univ. (China); Z. Wang, J. Hong, Y. Qiao, Anhui Institute of Optics and Fine Mechanics (China); Y. Chen, Anhui Agricultural Univ. (China)
- 6723 3P **Application research of vision technology in automobile radio panel measurement system** [6723-132]
X. Jin, S. Dai, P. Mu, Univ. of Shanghai for Science and Technology (China)
- 6723 3Q **NETD test of high-sensitivity infrared camera** [6723-133]
Y. Li, D. Pan, C. Yang, Y. Luo, Huazhong Institute of Electro-Optics (China)
- 6723 3R **Research of surface acoustic wave acousto-electro-optic effect** [6723-134]
T. Liu, K. Yu, S. He, S. Hu, Beijing Univ. of Technology (China)
- 6723 3S **Radar and infrared data fusion algorithm based on fuzzy-neural network** [6723-135]
F. Han, W. H. Yang, Xidian Univ. (China)
- 6723 3T **Measurement of paraboloid surface workpiece with zero error sum** [6723-136]
J. Yang, Changchun Univ. of Science and Technology (China) and Jilin Province Economics and Management Cadres College (China); C. Tian, Q. Liu, H. Yang, Z. Hao, Changchun Univ. of Science and Technology (China)
- 6723 3U **Primary study on ellipsometry of large roughness surface** [6723-137]
Z. Huang, L. Wang, Z. He, J. Chen, South China Normal Univ. (China)
- 6723 3V **Real-time monitoring of thin films' optical thickness at shut-turning point with fuzzy logic** [6723-138]
H. Zhang, Univ of Shanghai for Science and Technology (China) and Tongji Univ. (China); X. Jian, Univ. of Shanghai for Science and Technology (China); B. Zhou, Tongji Univ. (China)
- 6723 3W **Research on effects of phase error in phase-shifting interferometer** [6723-139]
H. Wang, Xi'an Jiaotong Univ (China) and Xi'an Univ. of Technology (China); Z. Wang, H. Zhao, Xi'an Jiaotong Univ. (China); A. Tian, B. Liu, Xi'an Univ. of Technology (China)

- 6723 3X **Research on moiré fringe information extraction based on warpage measurement** [6723-140]
P. Zhong, Dong Hua Univ. (China); J.-X. Qiu, Shanghai Univ. of Engineering Science (China)
- 6723 3Y **High-resolution digital holography for shape measurement of microscopic object** [6723-141]
H. Wang, Hebei Univ of Engineering (China) and Beijing Univ. of Technology (China);
B. Zhao, Hebei Univ. of Engineering (China); D. Wang, Beijing Univ. of Technology (China);
G. Wang, Beijing Univ. of Technology (China) and Henan Institute of Metrology (China);
J. Zhao, Beijing Univ. of Technology (China)
- 6723 3Z **Research on temperature and strain characteristics of metallized FBG** [6723-142]
B. Wang, W. Yan, R. Shen, J. Zhang, Y. Wang, Dalian Univ. of Technology (China)
- 6723 40 **Sensitivity of magneto-optic method for measuring beat-length of high birefringence optical fiber** [6723-143]
H.-H. Bao, Z.-D. Shi, Shanghai Univ. (China); J.-Q. Lin, Guangxi Institute of Technology (China); S. Liu, X.-N. Xiang, Shanghai Univ. (China)
- 6723 41 **Characterization of curved composite structure using laser infrared photothermal radiometry** [6723-144]
Z. Chen, C. Wang, H. Qu, Suzhou Univ. (China)
- 6723 42 **Photovoltaic effect of different thickness vanadium oxide thin film** [6723-145]
X. Wei, Z. Wu, T. Wang, S. Li, J. Tang, Y. Jiang, Univ. of Electronic Science and Technology of China (China)
- 6723 43 **Application of two-frequency laser interferometer in dynamic calibrating of long displacement sensor** [6723-146]
W. Dong, B. Wu, F. Sun, Chengdu Univ. (China)
- 6723 44 **New photoelectric method for inside cylindricity measurement** [6723-147]
H. Yu, Z. Zhao, Y. Zhao, M. Xu, Nanjing Univ. of Aeronautics and Astronautics (China)
- 6723 45 **Demodulation method of active homodyne laser vibration measurement system based on DSP** [6723-148]
D. Wan, J. Yang, Z. Liu, L.Yuan, Harbin Engineering Univ. (China)

Part Three

- 6723 46 **Spectral resolution of space-borne Fourier transform spectrometer** [6723-149]
P. Liu, P. Wang, J. Hua, H. Wang, Shanghai Institute of Technical Physics (China)
- 6723 47 **Optical fiber frequency shift profilometry** [6723-150]
X. Lin, J. Cui, L. Yuan, Harbin Engineering Univ. (China)
- 6723 48 **Three-dimensional profile measurement of steep object by optical fiber frequency mixing fringe projection technology** [6723-151]
X. Lin, L. Yuan, Harbin Engineering Univ. (China)

- 6723 49 **Virtual orthogonal grid method for calibrating structured light binocular vision measurement system** [6723-152]
Q. Dai, T. Geng, H. Deng, W. Ren, J. Liu, Harbin Engineering Univ. (China)
- 6723 4A **Research on optoelectronic image identifying technology of biomolecule encoding** [6723-153]
B. Li, X. Yuan, Y. Cao, Huazhong Univ. of Science and Technology (China)
- 6723 4B **Modeling and analysis of the mathematic model of differential astigmatic optical system used for the FPC (flexible printed circuit) online detection system** [6723-154]
Z. Yuan, J. Zhang, F. Long, L. Zhang, Xiamen Univ. (China)
- 6723 4C **Laboratory radiation calibration experiments of TDI CCD camera** [6723-155]
Y. Liu, Beijing Institute of Clothing Technology (China)
- 6723 4D **Infrared spectra analysis method of multi-component mixed gas concentration based on support vector machine** [6723-156]
W. Xie, P. Bai, L. Xiao, Air Force Engineering Univ. (China)
- 6723 4E **Measurement of refractive index in optical fiber prefabricated stick with scanning method** [6723-157]
H. Zhou, Univ. of Shanghai for Science and Technology (China) and Donghua Univ. (China); J. Chen, Univ. of Shanghai for Science and Technology (China); Q. Gao, Donghua Univ. (China)
- 6723 4F **Design of drivers for tiny LCD reticule image generator used for optical measurement** [6723-158]
H. Liu, J. Lin, R. Sun, Beijing Institute of Technology (China)
- 6723 4G **Application of semiconductor laser on big dimension measuring system** [6723-159]
H. Zhang, X. Zhai, X. Zhou, Armor Technique Institute of PLA (China); Y. Bi, Society Development Servicing Ctr. of Jilin Province (China); G. Di, X. Han, Armor Technique Institute of PLA (China)
- 6723 4H **Singularity analysis of pavement surface images** [6723-160]
G. Wang, Nanjing Univ. of Information Science and Technology (China) and LuDong Univ. (China); A. He, L. Xiao, Nanjing Univ. of Information Science and Technology (China)
- 6723 4I **Gas cell based on cascaded GRIN lens for optical fiber gas sensor** [6723-161]
J. Sa, Y. Chen, G. Zhang, Z. Zhou, L. Cui, Huazhong Univ. of Science and Technology (China)
- 6723 4J **Study on high speed dual-frequency laser interferometry in two longitudinal modes** [6723-162]
T. Zhang, C. Yang, Sichuan Univ. (China); W. Dong, B. Wu, Chengdu Univ. (China)
- 6723 4K **Study and application of high accuracy and long size measurement based on machine vision** [6723-163]
L. Yang, Y. Shan, X. Zhang, China Jiliang Univ. (China)

- 6723 4L **Reconstruction of off-axis lensless Fourier transform digital holograms based on angular spectrum theory** [6723-164]
G. Wang, Beijing Univ. of Technology (China) and Henan Institute of Metrology (China); H. Wang, Beijing Univ. of Technology (China) and Hebei Univ. of Engineering (China); D. Wang, J. Xie, J. Zhao, Beijing Univ. of Technology (China)
- 6723 4M **Novel measurement for large dimensions based on two-longitudinal mode thermal frequency-stabilized He-Ne laser** [6723-165]
B. Wu, W. Dong, Chengdu Univ. (China)
- 6723 4N **Novel measurement method for selective laser sintering transient temperature field** [6723-166]
J. Xing, Harbin Engineering Univ. (China) and Harbin Institute of Technology (China); J. Sun, Harbin Engineering Univ. (China); Y. Gao, Nanchang Institute of Aeronautical Technology (China)
- 6723 4O **Research on the affect of differential-images technique to the resolution of infrared spatial camera** [6723-167]
G. Jin, Changchun Institute of Optics, Fine Mechanics and Physics (China); Y. An, Y. Qi, F. Hu, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China)
- 6723 4P **Study on phase unwrapping algorithms in interferogram processing** [6723-168]
Y. Li, Shanghai Fisheries Univ. (China)
- 6723 4Q **Research on dual-purpose optical aspheric surface testing instrument** [6723-169]
J. Liu, Xiamen Univ. (China) and Xiamen Univ. of Technology (China); Y. Guo, G. Liu, Xiamen Univ. (China)
- 6723 4R **Interferogram region extrapolation technology by exemplar-based image inpainting** [6723-170]
J. Liu, Institute of Electrical Engineering (China) and Graduate Univ. of Chinese Academy of Sciences (China); Y. Li, Institute of Electrical Engineering (China) and Beijing Institute of Technology (China); K. Liu, Institute of Electrical Engineering (China) and Graduate Univ. of Chinese Academy of Sciences (China)
- 6723 4S **Experimental assessment on the performance of laser total station measurement system for FAST** [6723-171]
L. Zhu, R. Nan, X. Zhai, National Astronomical Observatories (China)
- 6723 4T **Zernike polynomials for evaluation of optical system in use** [6723-172]
B. Shan, B. Guo, H. Niu, S. Wang, Shenzhen Univ. (China)
- 6723 4U **New approaches to fabric fused-fiber M-Z interferometer type interleaver** [6723-173]
Y. Liu, Beijing Institute of Clothing Technology (China); G. Zhou, China Netcom Group Labs. (China)
- 6723 4V **Digital holography research on paraxial optical system** [6723-174]
J. Li, Y. Wu, R. Guo, Y. Fu, Kunming Univ. of Science and Technology (China)

- 6723 4W **Fast image processing on chain board of inverted tooth chain** [6723-175]
Q. Liu, Hangzhou Dianzi Univ. (China); G. Li, Jilin Univ. (China)
- 6723 4X **Aggregate particle image segmentation** [6723-176]
W. X. Wang, Chongqing Univ. of Posts and Telecommunications (China)
- 6723 4Y **Measurement of the micro-displacement of metal bar with ESPI-phaseshift method** [6723-177]
Z. Zheng, L. Chen, Z. Sun, Guangdong Univ. of Technology (China)
- 6723 4Z **Design of orienting and aiming instrument based on fiber optic gyroscope** [6723-178]
Z. Zhang, L. Wang, J. Sun, Jilin Univ. (China)
- 6723 50 **Effect of coupling effectiveness on fiber optical probe** [6723-179]
G. Hu, J. Zhang, P. Kang, Q. Lin, Xiamen Univ. (China)
- 6723 51 **Feature extraction of fog from multi-spectral infrared images of FY-2C geostationary satellite** [6723-180]
H. Fan, T. Liu, W. Xu, Donghua Univ. (China)
- 6723 52 **Effective indexes of refraction and limiting properties of ethyl red** [6723-181]
S. Qi, Dezhou Univ. (China) and Nankai Univ (China); Y. Liu, A. Liu, L. Jing, M. Li, J. Wang, Y. Hao, B. Wang, Dezhou Univ. (China)
- 6723 53 **Research on errors of half-waveplate and quarter-waveplates in polarized laser interferometer** [6723-182]
J. Yang, L. Duan, Z. Liu, L. Yuan, Harbin Engineering Univ. (China)
- 6723 54 **Online measurement for surface defects of running wheel set** [6723-183]
K. Wu, F. Zhuang, F. Zhu, T. Ye, Hangzhou Dianzi Univ. (China)
- 6723 55 **Aspheric surface test by digital moiré method** [6723-184]
Q. Zhu, Q. Hao, Beijing Institute of Technology (China)
- 6723 56 **Diode laser based continuous-wave cavity ring-down technique for high reflectivity measurement** [6723-185]
Y. Gong, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); B. Li, Institute of Optics and Electronics (China)
- 6723 57 **Laser output power stabilization for circular laser writing systems by using acousto-optic modulator** [6723-186]
D.-I. Kim, H.-G. Rhee, J.-B. Song, Y. W. Lee, Korea Research Institute of Standards and Science (South Korea)
- 6723 58 **Image segmentation based on bi-stable system** [6723-187]
X. Wang, Y. Yan, Hebei Univ. (China)
- 6723 59 **Research on key technologies of non-contact measurement system of optical aspheric surface** [6723-188]
G. Liu, Y. Guo, J. Liu, Xiamen Univ. (China)

- 6723 5A **Study on pattern formation in dielectric barrier discharge by optical method** [6723-189]
L. Dong, X. Li, P. Jia, Hebei Univ. (China)
- 6723 5B **Study on the diameter and discharge duration of filament in dielectric barrier discharge in air/argon** [6723-190]
Z. Yin, North China Electric Power Univ. (China); X. Li, Hebei Univ. (China); M. Huang, North China Electric Power Univ. (China); L. Dong, Hebei Univ. (China)
- 6723 5C **Discharge domain in dielectric barrier discharges in air at atmospheric pressure** [6723-191]
X. Li, P. Jia, L. Dong, Z. Yin, Hebei Univ. (China)
- 6723 5D **Application of laser bar code technology in power fitting evaluation** [6723-192]
X. Yang, North China Electric Power Univ. (China); S. Liu, Agricultural Univ. of Hebei (China)
- 6723 5E **Data preprocessing of the exterior field of vision assembling photogrammetric camera** [6723-193]
J. Liu, Changchun Institute of Optics, Fine Mechanics and Physics (China); J. Li, Changchun Univ. (China); G. Li, Z. Wang, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6723 5F **Study on the detection sensitivity of APS star tracker** [6723-194]
J. Li, Changchun Univ. (China); J. Liu, G. Li, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6723 5G **Smoothing of optical images using a partial differential equation** [6723-195]
H. Wang, North China Electric Power Univ. (China)
- 6723 5H **Research on reflecting performance of dopes for laser extinction chamber** [6723-196]
H. Li, National Univ. of Defense Technology (China) and 4th Dept. (China); Q. Chen, L. Feng, 4th Dept. (China); L. Zhang, B. Yang, Anhui Institute of Optics and Fine Mechanics (China)
- 6723 5I **Study on the emission spiral patterns by changing the sidewall of the discharge system** [6723-197]
S. Liu, L. Dong, F. Liu, Y. He, Hebei Univ. (China)
- 6723 5J **Argon ($2P \rightarrow 1S$) spectral lines measurement in dielectric barrier discharge (DBD) by optical emission spectroscopy** [6723-198]
L. Li, L. Dong, H. Wang, F. Liu, Hebei Univ. (China)
- 6723 5K **Method for removing temperature shifting during measurement of large mirrors in grinding process** [6723-199]
H. Jing, L. Kuang, B. Fan, Institute of Optics and Electronics (China)
- 6723 5L **Measurement of optical surfaces with knife edge method** [6723-200]
H. Jing, B. Fan, S. Wu, F. Wu, T. Fan, Institute of Optics and Electronics (China)
- 6723 5M **Analysis and simulation of an all-fiber polarization transformer** [6723-201]
Z.-D. Shi, M.-N. Ji, Shanghai Univ. (China); J.-Q. Lin, Guangxi Institute of Technology (China); H.-H. Bao, S. Liu, Shanghai Univ. (China)

- 6723 5N **Research and design of intelligent distributed traffic signal light control system based on CAN bus** [6723-202]
Y. Chen, ZhengZhou Institute of Aeronautical Industry Management (China)
- 6723 5O **Design of video processing and testing system based on DSP and FPGA** [6723-203]
H. Xu, J. Lv, X. Chen, X. Gong, C. Yang, China Jiliang Univ. (China)
- 6723 5P **Application of SPM interferometry in MEMS vibration measurement** [6723-204]
C. Tang, Chongqing Univ. (China); G. He, Chongqing Univ. (China) and Shanghai Institute of Optics and Fine Mechanics (China); C. Xu, Chongqing Univ. of Posts and Telecommunications (China); L. Zhao, J. Hu, Chongqing Univ. (China)
- 6723 5Q **Image sensor and its application in vibration distribution measurement** [6723-205]
G. He, Chongqing Univ. (China) and Shanghai Institute of Optics and Fine Mechanics (China); C. Tang, Chongqing Univ. (China); C. Xu, Chongqing Univ. of Posts and Telecommunications (China); L. Wang, X. Li, Chongqing Univ. (China)
- 6723 5R **Research on path planning and data processing system for high-precision aspheric measurement** [6723-206]
J. Ye, J. Guo, Y. Guo, Xiamen Univ. (China)
- 6723 5S **Design of twin computer-generated holograms used for testing concave conic mirrors** [6723-207]
Y. Xie, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); Q. Chen, F. Wu, Institute of Optics and Electronics (China)
- 6723 5T **High precision sensing system for vibration distribution measurement** [6723-208]
G. He, Chongqing Univ. (China) and Shanghai Institute of Optics and Fine Mechanics (China); C. Tang, L. Zhao, M. Fu, Chongqing Univ. (China)
- 6723 5U **Novel interferometry for crystal thickness measurement** [6723-209]
L. Zhao, C. Tang, Chongqing Univ. (China); G. He, Chongqing Univ. (China) and Shanghai Institute of Optics and Fine Mechanics (China); X. Li, M. Fu, Chongqing Univ. (China)
- 6723 5V **SPM interferometer with large range for mirco-vibration measurement** [6723-210]
M. Fu, C. Tang, Chongqing Univ. (China); G. He, Chongqing Univ. (China) and Shanghai Institute of Optics and Fine Mechanics (China); J. Hu, L. Wang, Chongqing Univ. (China)
- 6723 5W **Optical constants measurement system for α :H silicon film** [6723-211]
Q. Jiang, Z. Lin, J. Cheng, K. Qi, C. Ge, Univ. of Electronic Science and Technology of China (China)
- 6723 5X **Analysis of array illumination generalized by the combination of a binary phase grating and a lens** [6723-212]
H. Wang, Shanghai Univ. of Electric Power (China)
- 6723 5Y **Application of a single phase array plate for implementing phase-shift of a digital hologram** [6723-213]
H. Wang, Shanghai Univ. of Electric Power (China); Y. Yu, Shanghai Univ. (China)

- 6723 5Z **Tracing platform for infrared laser atmospheric communication between warships**
[6723-214]
J. Sun, X. Zhang, Harbin Engineering Univ. (China); M. Wang, Harbin Univ. of Commerce
(China); J. Xing, E. Sang, Harbin Engineering Univ. (China)
- 6723 60 **Online extrinsic parameter calibration of stereo vision coordinate measurement system**
[6723-215]
Q. Xu, D. Ye, R. Che, Q. Fan, Harbin Institute of Technology (China)
- 6723 61 **Compensator design for aspheric testing using virtual glass model** [6723-216]
Y. Jiang, P. Wang, Y. Qi, N. Wei, Beijing Institute of Technology (China)
- 6723 62 **Design of a CGH wavefront generator for aspheric testing with wavefront tracing method**
[6723-217]
Y. Qi, P. Wang, Y. Jiang, Beijing Institute of Technology (China)
- 6723 63 **Design and application of a set of equipment to test the attenuation performance of
aerosol to 10.6 μ m laser emission** [6723-218]
X. Wang, Institute of Chemical Defense (China)

ADDITIONAL PAPERS

- 6723 64 **Design and evaluation of corner compensation patterns for anisotropic etching** [6723-219]
X. Chen, D. W. Lee, J. S. Park, Chonnam National Univ. (South Korea)
- 6723 65 **Focal plane location in digital holography** [6723-220]
Y. Yang, Chongqing Institute of Technology (China) and Chonnam National Univ.
(South Korea); B. Kang, Chonnam National Univ. (South Korea); Y. Choo Korea Atomic
Energy Research Institute (South Korea)

Author Index

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Secretary General of the Symposium

Li Yang, Committee of Optical Manufacturing Technology, COS
(China)

Introduction

Optical manufacturing technology has seen tremendous progress especially during the last 10 years both in China and abroad. It plays remarkable supporting and enabling roles in many industries and contributes to technology and society development. Optical manufacturing technology has become a very important interdisciplinary field of manufacturing science and optical science. It is closely associated with developments in information technologies, bioscience, materials, nanotechnologies, etc. At the same time, optical manufacturing has developed into a new global business involving optics, optoelectronics, and photonics in the world economy system. Today, as China becomes an integral part of the global economy, it is hard to find an area of optical manufacturing or optical market that doesn't involve the close cooperation between China and the rest of the world.

To satisfy the needs for timely exchanges of optical manufacturing technologies and market information, the first international symposium on Advanced Optical Manufacturing and Testing Technology (AOMATT) was sponsored and organized by the Chinese Optics Society (COS), The Institute of Optics and Electronics (IOE) of Chinese Academy of Science (CAS), and SPIE in 2000. Prof. WANG Daheng, a leading authority of Chinese optics and optical engineering and an academician of both the Chinese Academy of Science and Chinese Academy of Engineering, chaired the first successful AOMATT symposium in Chengdu, China. The first AOMATT in 2000 resulted in 106 papers published in the Proceedings of SPIE, Vol. 4231. A much larger second AOMATT meeting was held in Xian, China, in 2005. It resulted in 359 papers published in the Proceedings of SPIE, Vols. 6148–6150. The third AOMATT symposium came back to Chengdu, China, in July 2007. By all accounts, it was even a bigger success. More than 700 delegates from all over the world attended the opening ceremony and plenary session on the first day of the symposium. A total of 483 oral and poster papers were presented at the symposium. They are published in the Proceedings of SPIE, Vols. 6721–6724.

Professor ZHOU Bingkun, AOMATT 2007 Symposium General Chair, President of the Chinese Optical Society, and Academician of Chinese Academy of Science, chaired the opening ceremony and the plenary presentation, and gave its congratulations to the symposium in his opening speech. Professor CAO Jinghua, Vice Director of the Bureau of International Co-operation of Chinese Academy of Science, attended the opening ceremony and gave a warm opening speech. Dr. Philip Stahl from NASA Marshall Space Flight Center, a member of SPIE's Board of Directors and Vice President of ICO, represented SPIE at the symposium and delivered the first symposium plenary presentation entitled "James Webb Space Telescope: The First Light Machine." It was warmly received by the symposium delegates. Other symposium plenary speakers include Dr. Bernard Delabre from

ESO of Germany, Dr. Eric Ruch from REOSC of France, Dr. Jim Burge from the University of Arizona of USA, Dr. David Walker from Univ. College London of UK, Dr. Yoshiharu Namba from Chubu University of Japan, Dr. Tadashi Hatano from Tohoku University of Japan, Dr. Masaomi Kameyama from Nikon Corporation of Japan, Dr. Xiangang Luo from IOE of China, and Dr. Sen Han from Veeco Corporation, USA. The plenary presentations have given symposium delegates the opportunity to learn about the latest developments in large mirror and telescope technology, advanced optical manufacturing technology, optical testing, and nanotechnologies. The symposium has provided an excellent platform for all delegates to network with each other, review progresses in their fields, discuss future technology and market trends, explore collaboration and business opportunities, etc.

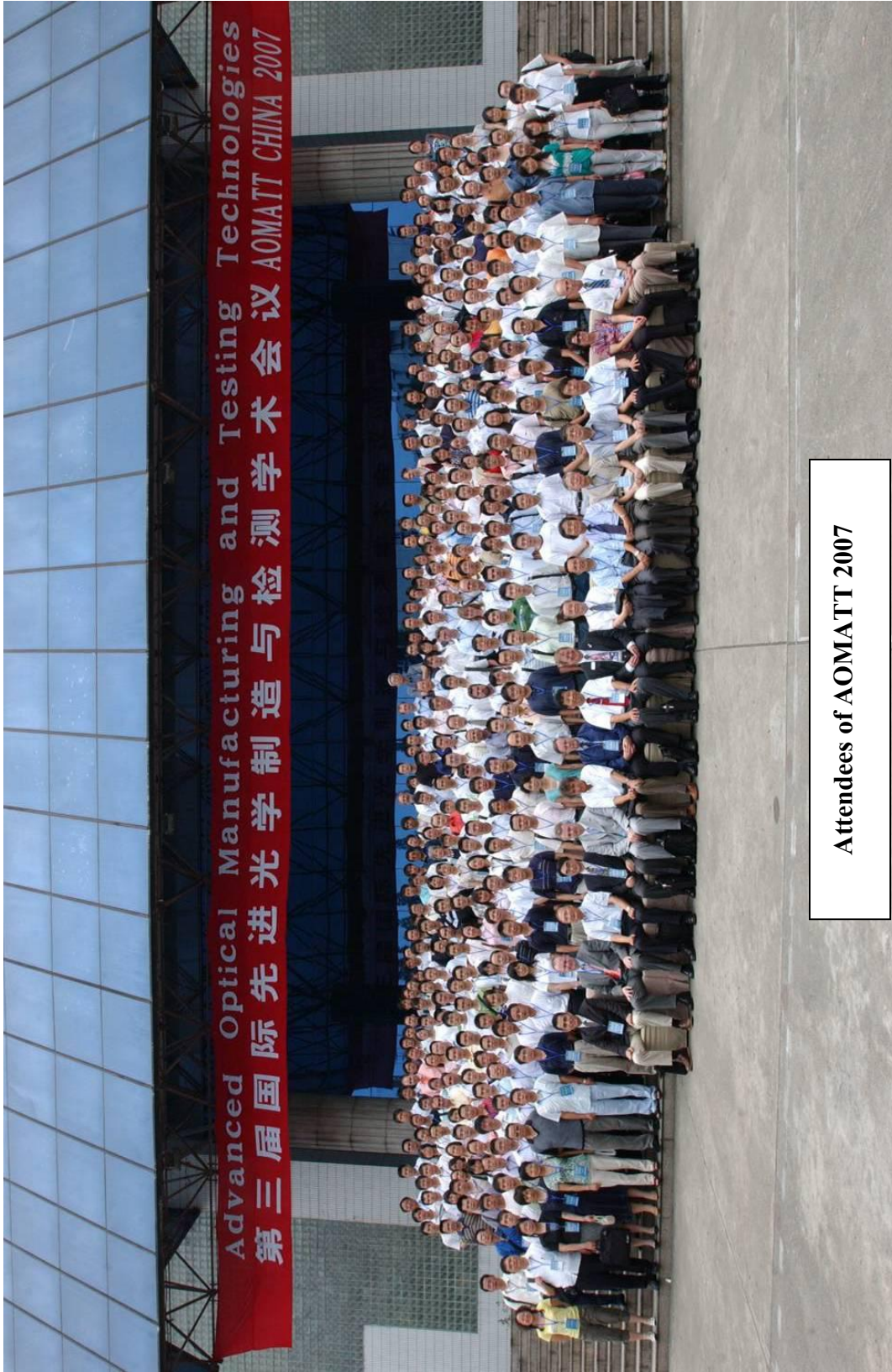
We are delighted that each new AOMATT symposium is more successful than the last. AOMATT has established itself as a must-attend leading optical design and manufacturing symposium in China. We are confident the meeting will get even better in the future and become a well-known international symposium. We would like to express our sincere appreciation to all organizations and individuals who have contributed to the success of AOMATT. We want to thank all authors and symposium delegates for attending the symposium and sharing their research and development with their colleagues around the world. The next AOMATT symposium will be held in China in 2009. We are looking forward to seeing you all at an even more successful AOMATT.

Li Yang

Secretary General, AOMATT 2000, 2005, 2007
Chairman of the Committee on Optical Manufacturing Technology of Chinese
Optical Society

Jinxue Wang

Deputy Secretary General, AOMATT 2007
Raytheon Santa Barbara Remote Sensing



Attendees of AOMATT 2007

